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P/1805-17

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

New York, New York

Markus TURPINEN

Date: November 4, 2005

Serial No.: 10/526,831

Group Art Unit: 2856

Filed: July 20, 2005

Examiner: ---

For: CHARACTERISATION OF PAPER

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

SUBMISSION

Sir:

Submitted herewith is a copy of a search report issued by a patent searching authority other than the PTO and the cited art together with a form listing the same for the convenience of the Examiner.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, VA 22313-1450, on November 4, 2005

Respectfully submitted,

Robert C. Faber

Name of applicant, assignee or  
Registered Representative

Signature

November 4, 2005

Date of Signature

Robert C. Faber

Registration No.: 24,322

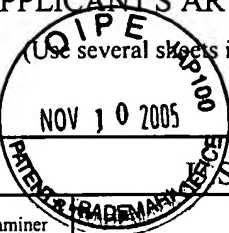
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Enclosures

<b>APPLICANT'S ART CITATION</b> (Use several sheets if necessary) 		Application 10/526,831		OFGS File No. P/1805-17		
		Applicant Markus Turtinen				
		Filing Date July 20, 2005		Group Art Unit 2856		
U.S. PATENT DOCUMENTS (not submitted for applications filed after 6/30/03)						
Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-					
	US-					
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	US-					
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	US-					
FOREIGN PATENT DOCUMENTS						
	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation
						Yes      No
	10318937	12-1998	Japan			x
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)						
	Jukka Iivarinen, <i>An Adaptive Texture and Shape Based Defect Classification</i> , Fourteenth International Conference on Pattern Recognition, Brisbane, Australia, August 1998.					
	Ari Visa, <i>Identification of Stochastic Textures with Multiresolution Features and Self-organizing Maps</i> , Proceedings 10 <sup>th</sup> International Conference on Pattern Recognition, 16-21 June 1990, Vol. I, pp. 518-522.					
	Ari Visa, <i>A Texture Classifier Based on Neural Network Principles</i> , International Joint Conference on Neural Networks, June 17-21, 1990, San Diego, Vol. I, pp. 491-496.					
Examiner		Date Considered				
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.						